



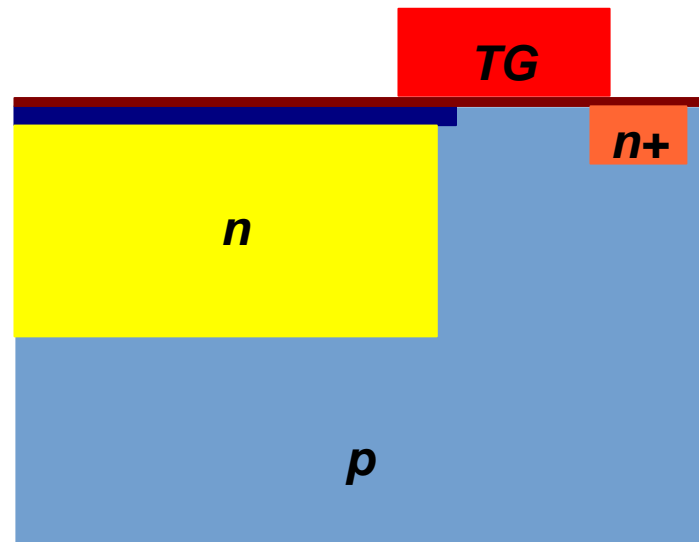
THAYER SCHOOL OF  
ENGINEERING  
AT DARTMOUTH

# TCAD Modeling of Devices for Quanta Image Sensors

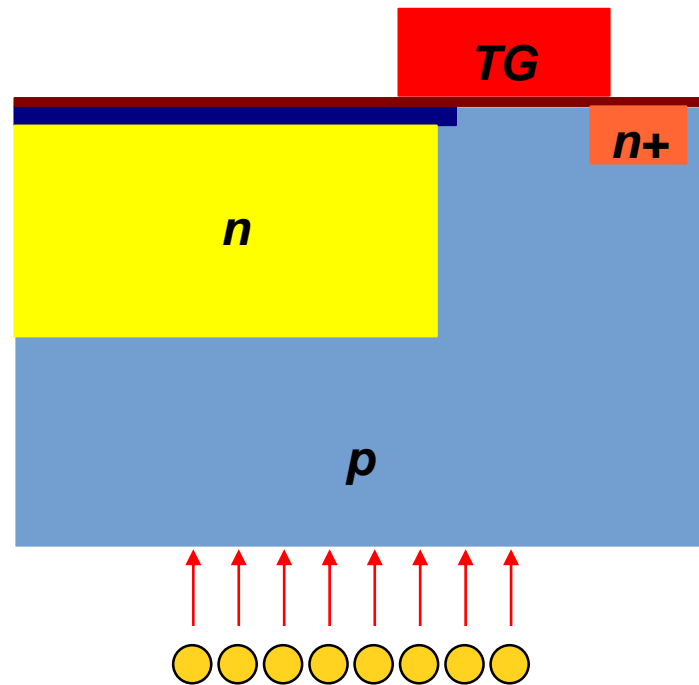
Jiaju Ma and Eric R. Fossum

1 April 2015

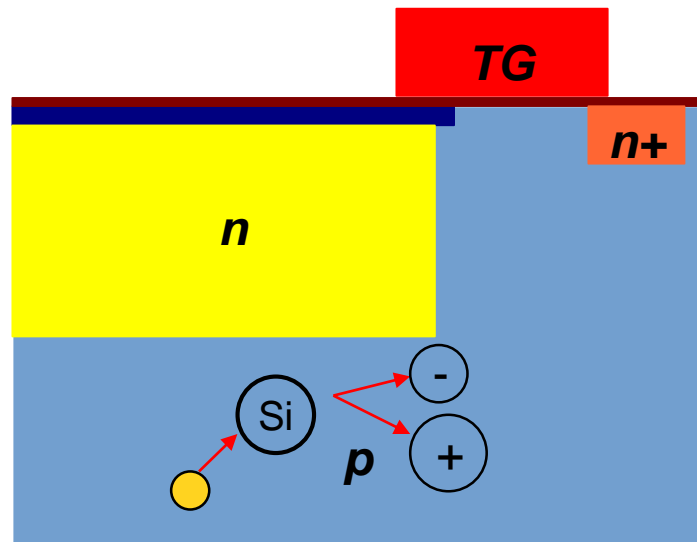
## Review of CMOS Image Sensor with a pinned photodiode



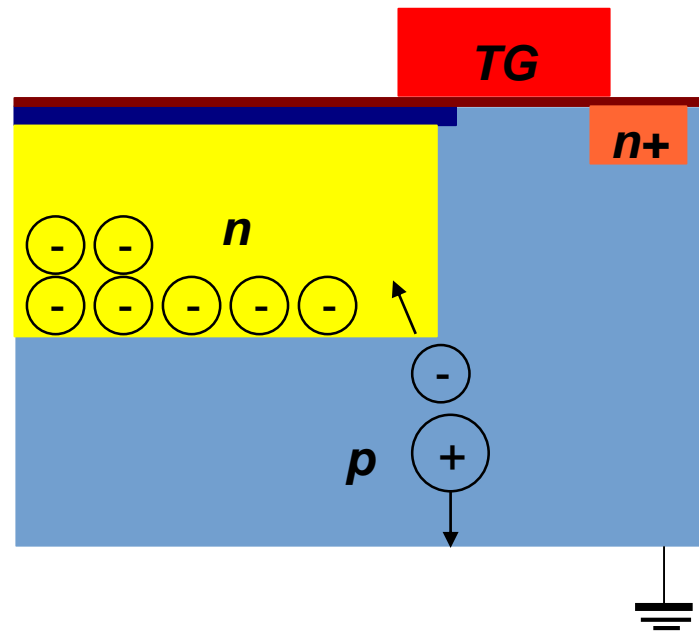
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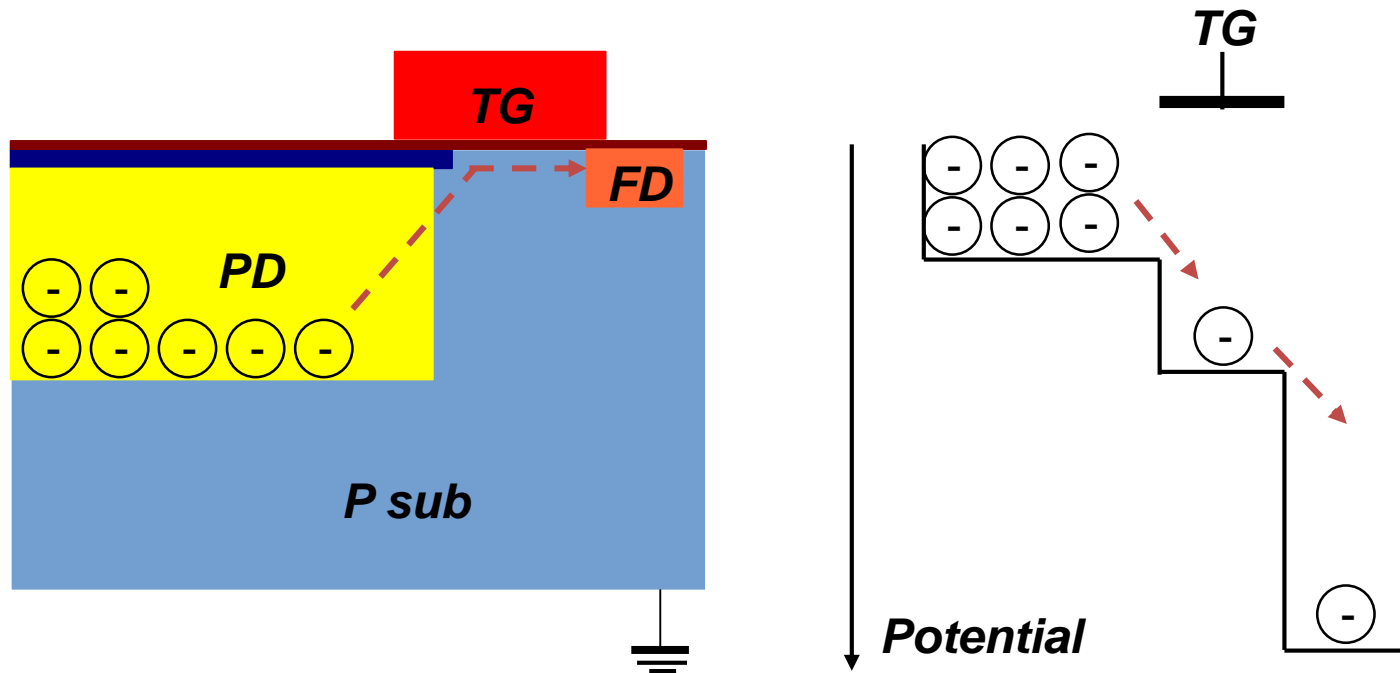
## Review of CMOS Image Sensor with a pinned photodiode



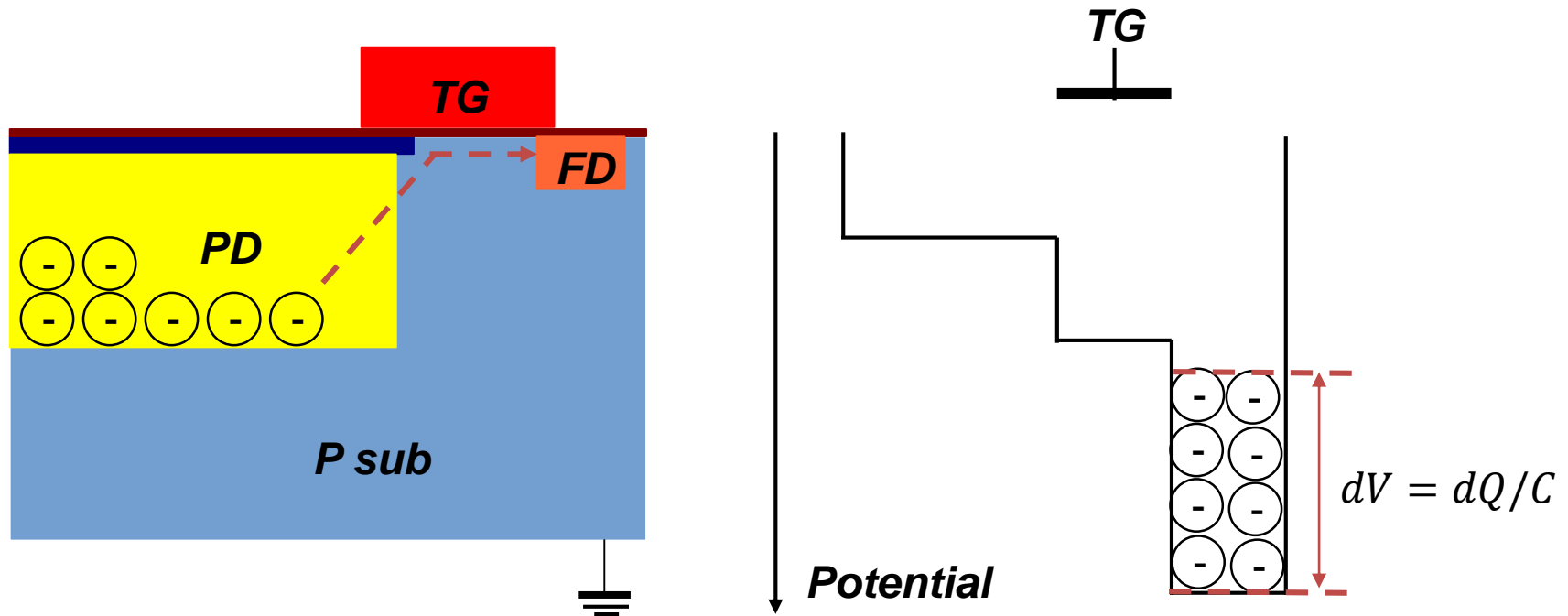
## Review of CMOS Image Sensor with a pinned photodiode



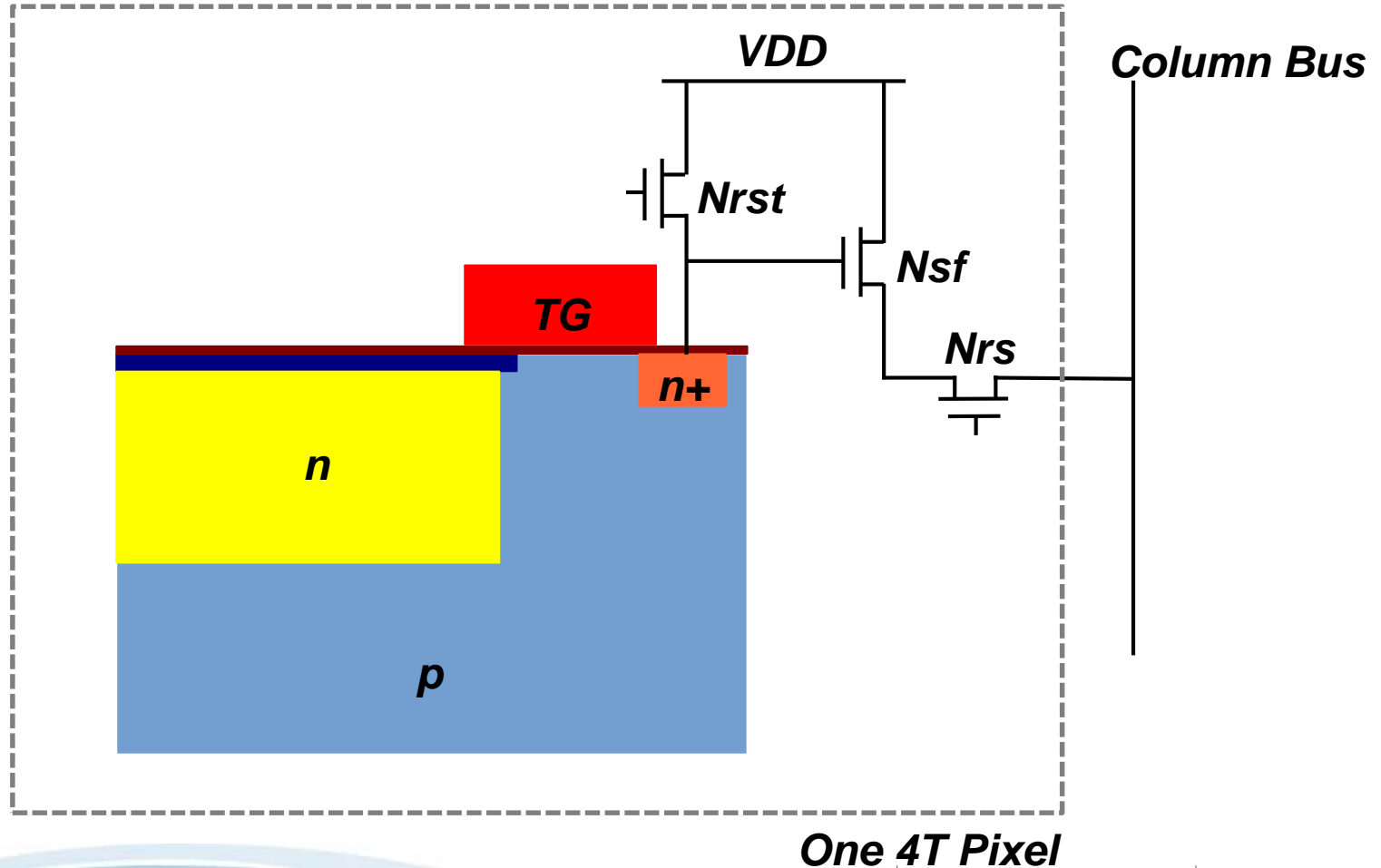
## Review of CMOS Image Sensor with a pinned photodiode



## Review of CMOS Image Sensor with a pinned photodiode



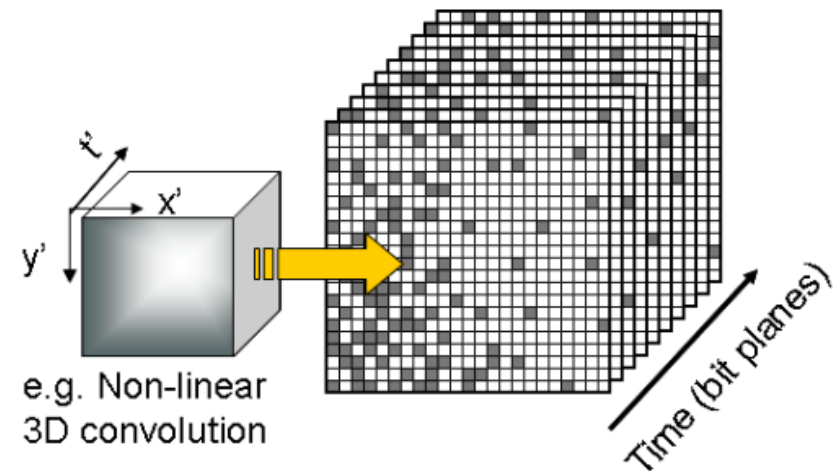
## Review of CMOS Image Sensor with a pinned photodiode





## Quanta Image Sensor (QIS) Concept

- The goal for QIS is to make a very **tiny**, specialized pixel (“jot”) which could sense a **single** photo-electron and output **binary** data.
- Jots array would be readout by scanning at a **high frame rate** to avoid likelihood of multiple hits in the same jot and loss of accurate counting.
- Image pixels could be created by combining jot data over a local **spatial** and **temporal** region using image processing.



## Quanta Image Sensor (QIS) Motivation

- Photons are digital in nature according to particle view of light and can be represented by binary data
- Better images can be obtained by oversampling in time and space.
- More applications, such as motion blur correction.



## Jot Device Concept

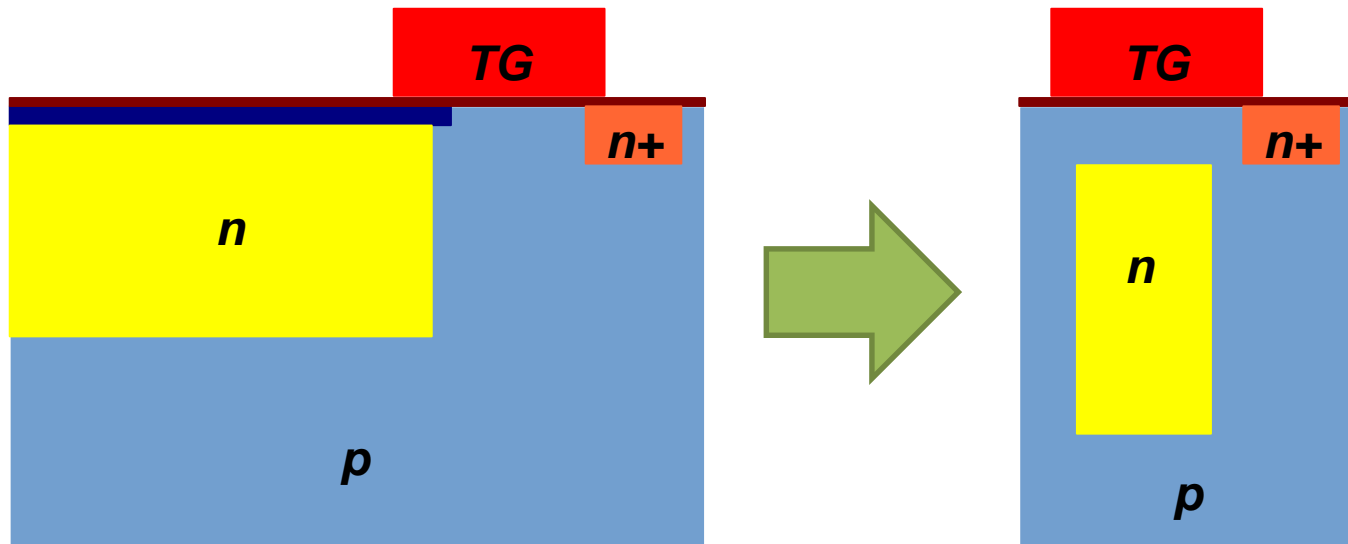
Specialized **tiny** pixel, sensing **single** photo-electron, output **binary** data

	Jot	Pixel
Size	650nm(10L)	1.1um*(17L)
Storage Capacity	1-100e-	~10000e-
Conversion Gain	>1mV/e-	100uV/e-
Read Noise	0.15e- rms	~2e- rms

**\*65nm CMOS CIS process**

## Jot Device Design

*Shrink size*



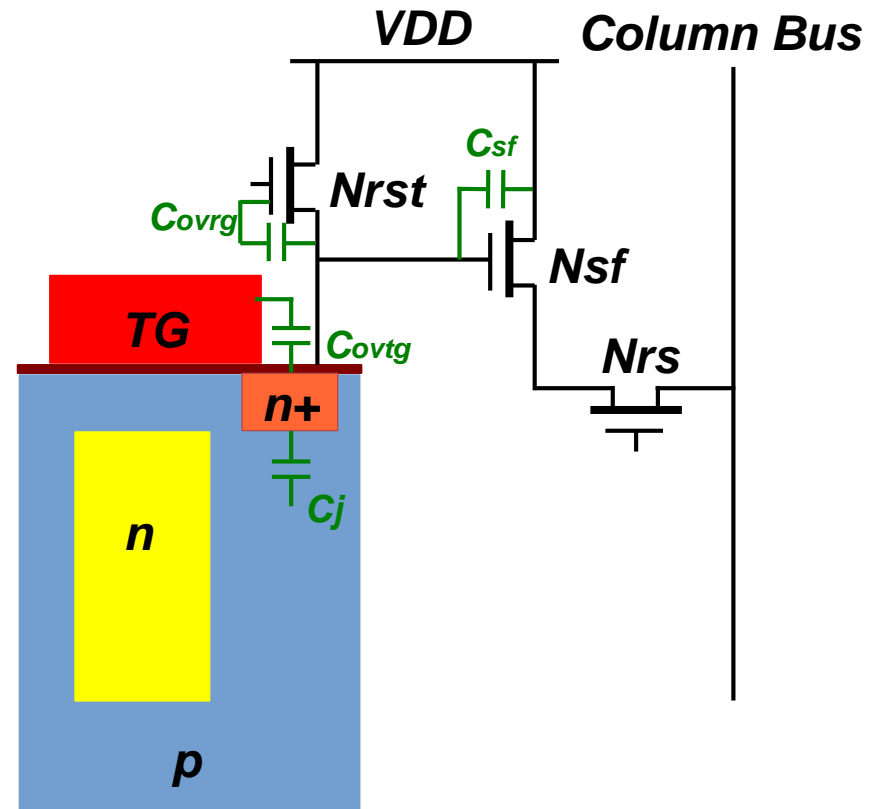
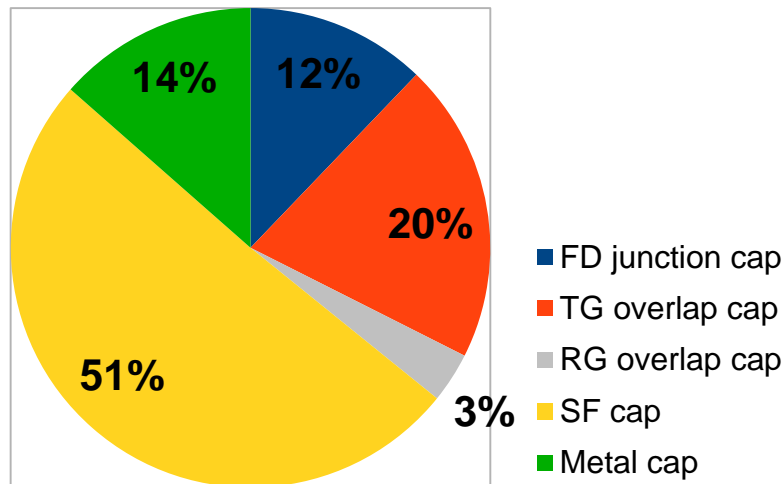
# Jot Device Design

Improve sensitivity

$$dV = dQ / C_{FD}$$

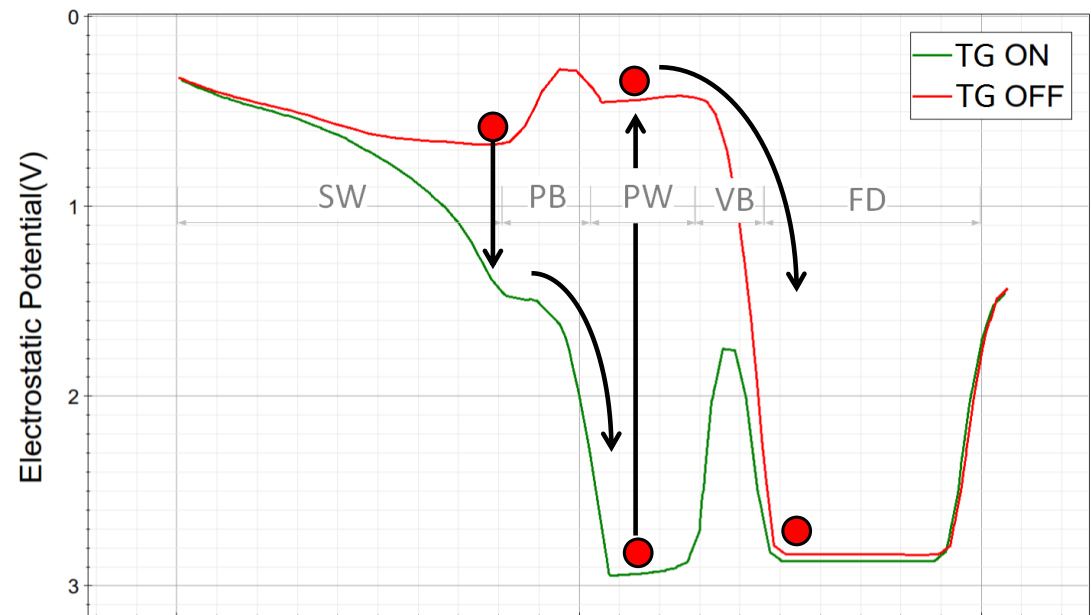
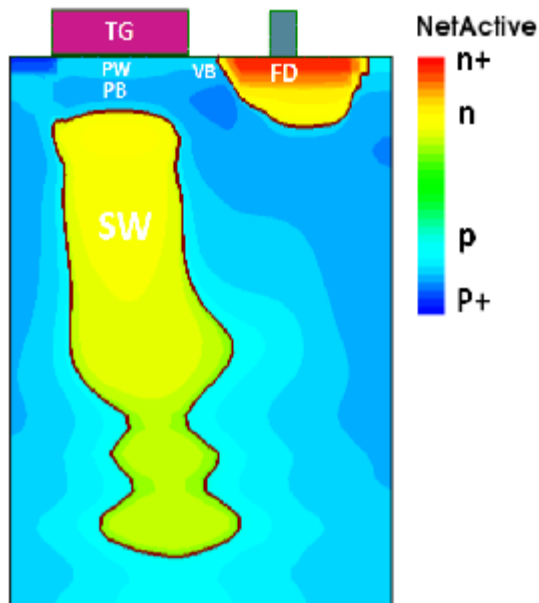
$$C.G. = \frac{dV}{dQ} = \frac{1}{C_{FD}}$$

$$C_{FD} = C_j + C_{ovtg} + C_{ovrg} + C_{sf} + C_{metal}$$

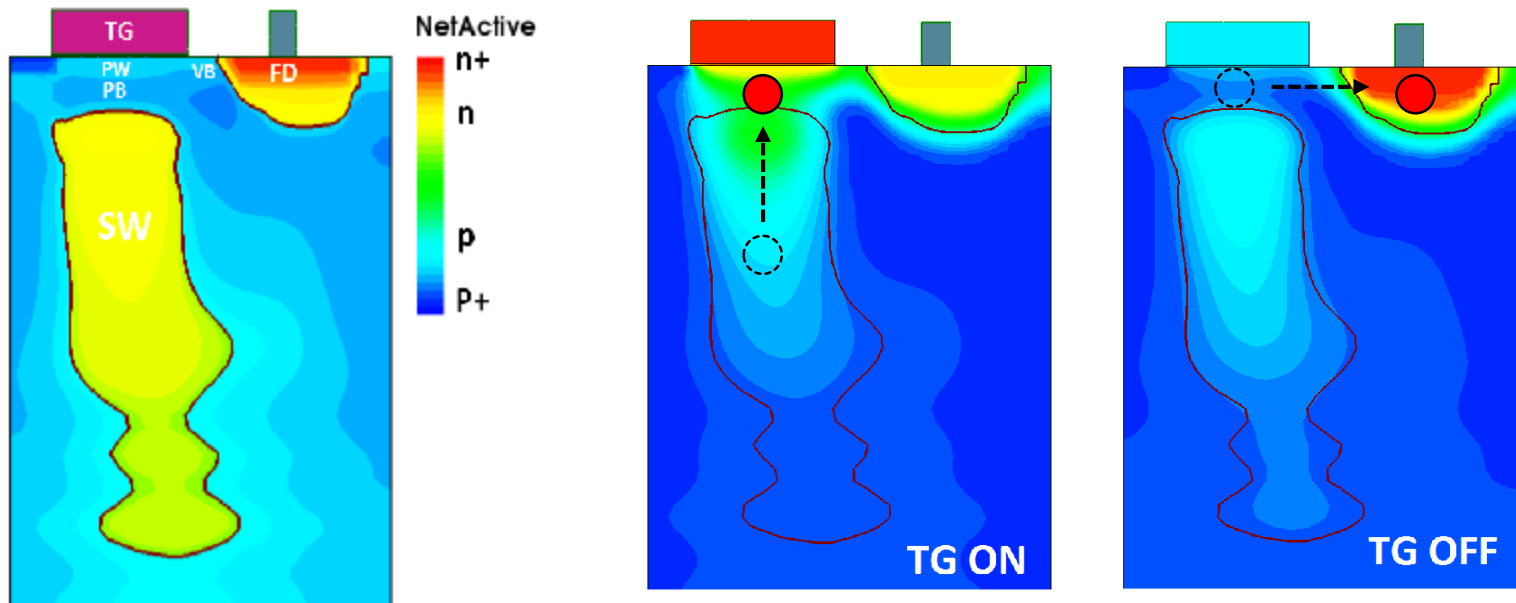


\*1.4um PPD Pixel  
 $C_{FD} = 1.55fF$   
 $C.G. = 103uV/e^-$

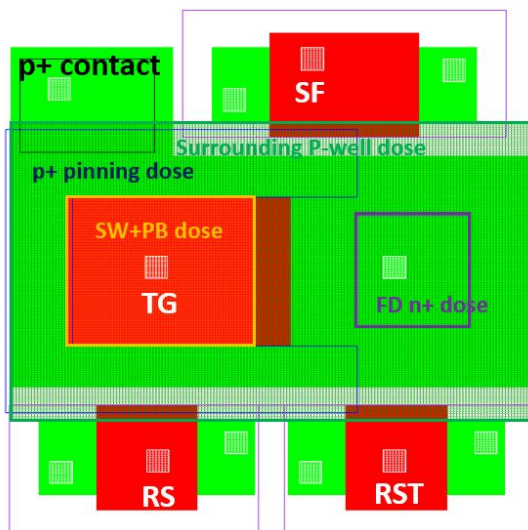
# Pump gate charge transfer



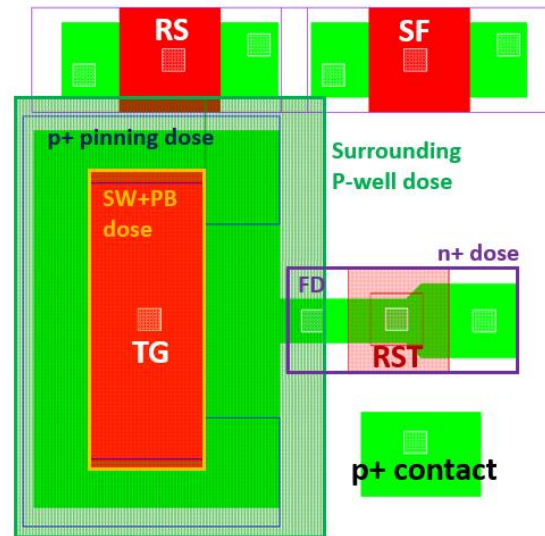
## Pump gate charge transfer



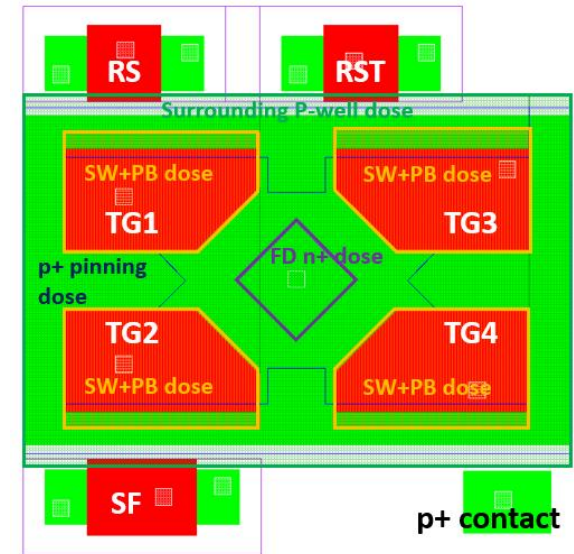
## Tape-out chip with 65nm CIS process



*Jot with pump gate TG  
1.4um, FWC=200e-*



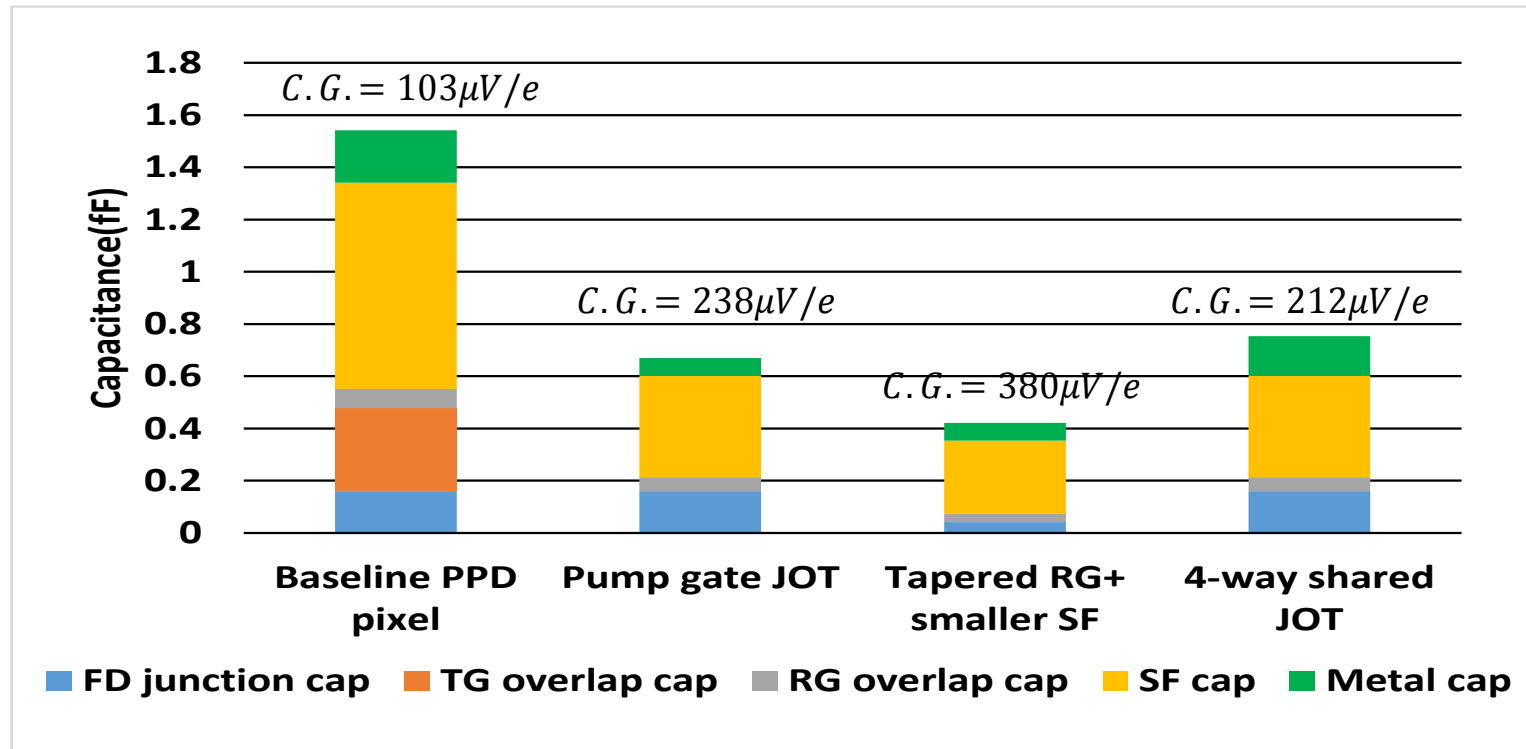
*Jot with pump gate TG  
and tapered RG  
1.4um, FWC=200e-*



*Jot with pump gate TG  
and 4-way shared readout  
1 um, FWC=200e-*

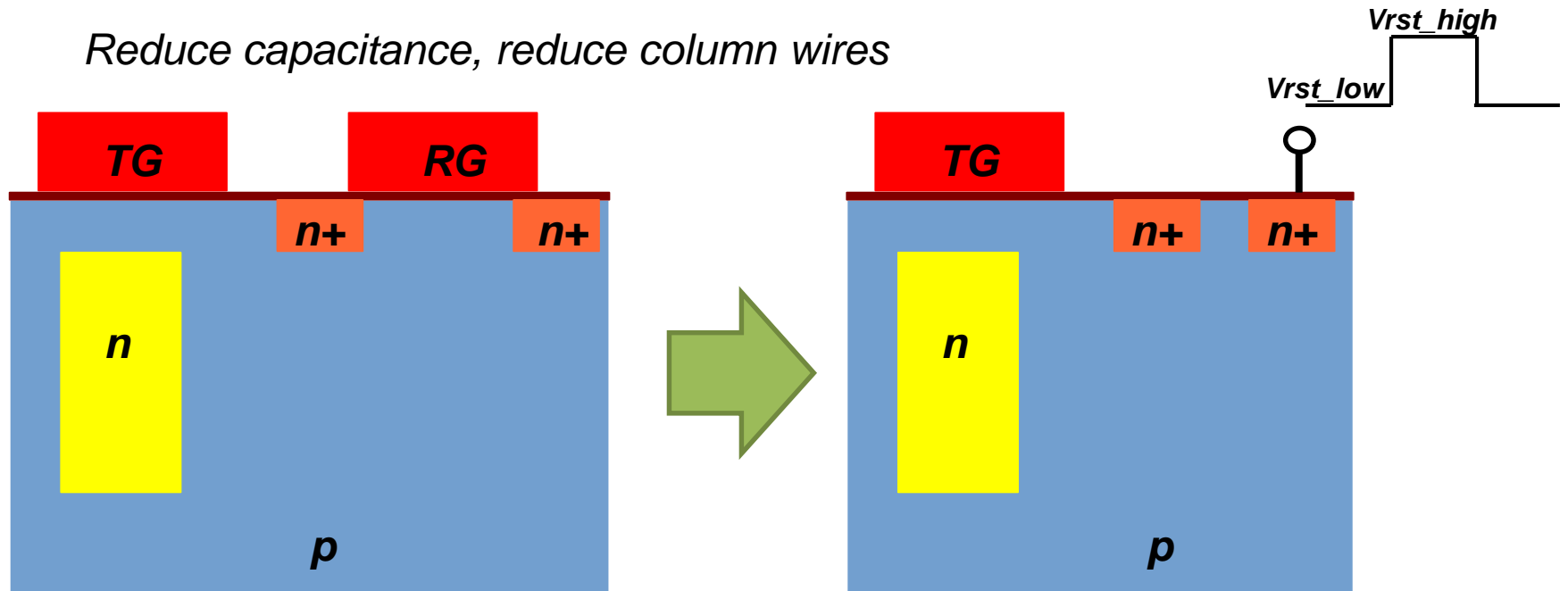


## Tape-out chip with 65nm CIS process

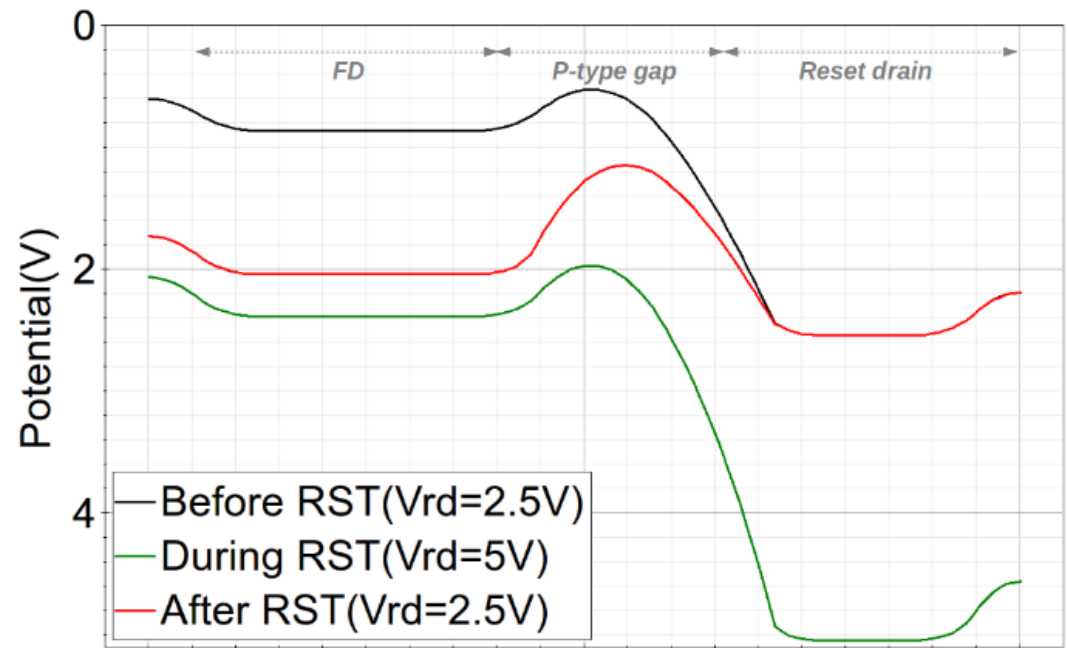
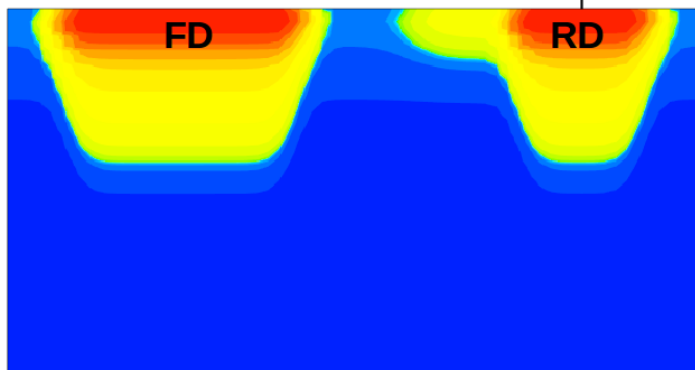
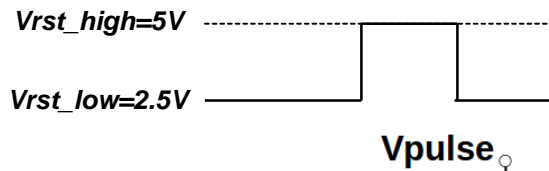


## Gate-less Reset

*Reduce capacitance, reduce column wires*

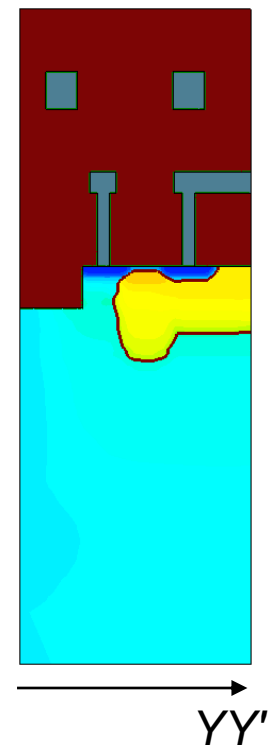
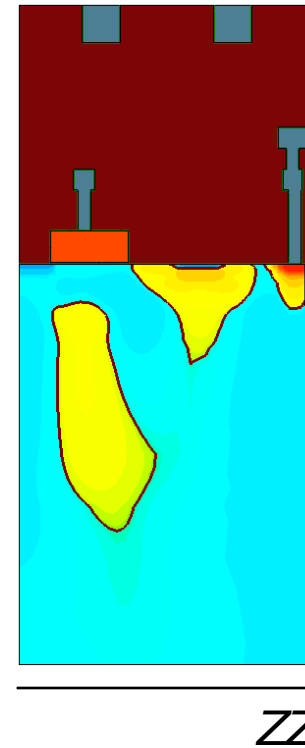
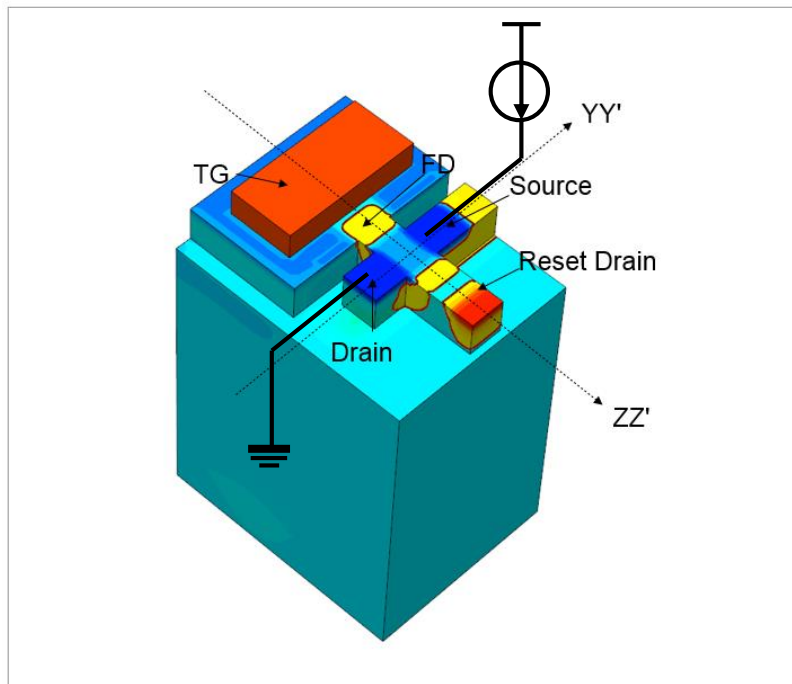


# Gate-less reset

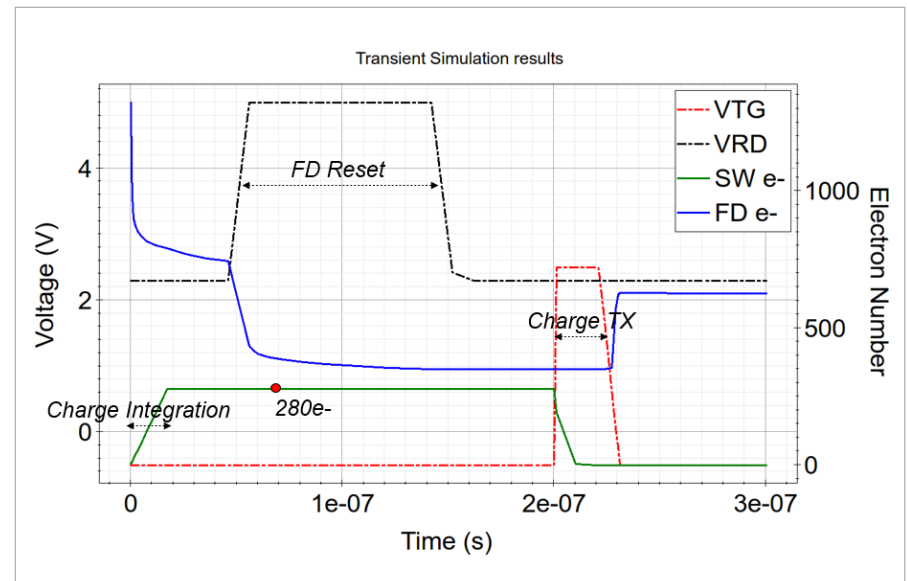
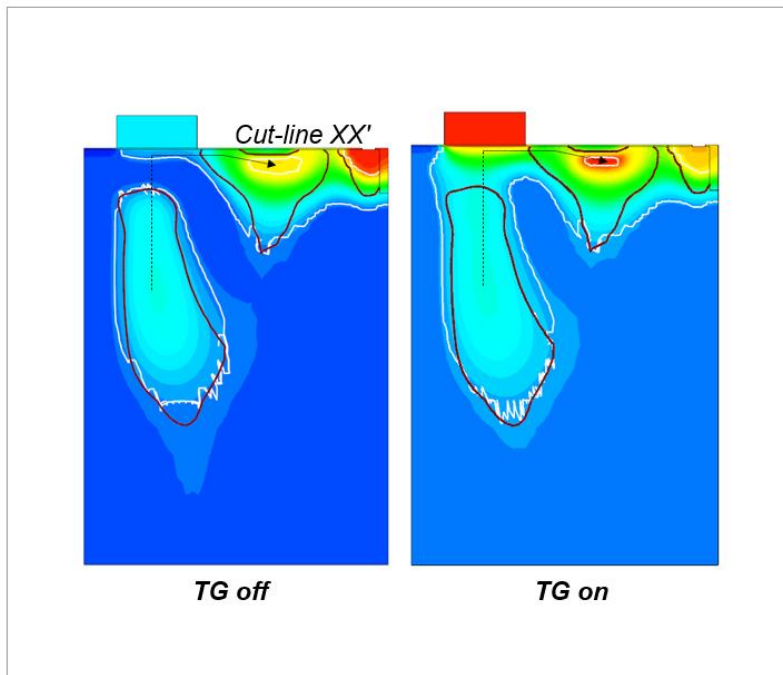


## JFET source follower with FD being the virtual gate

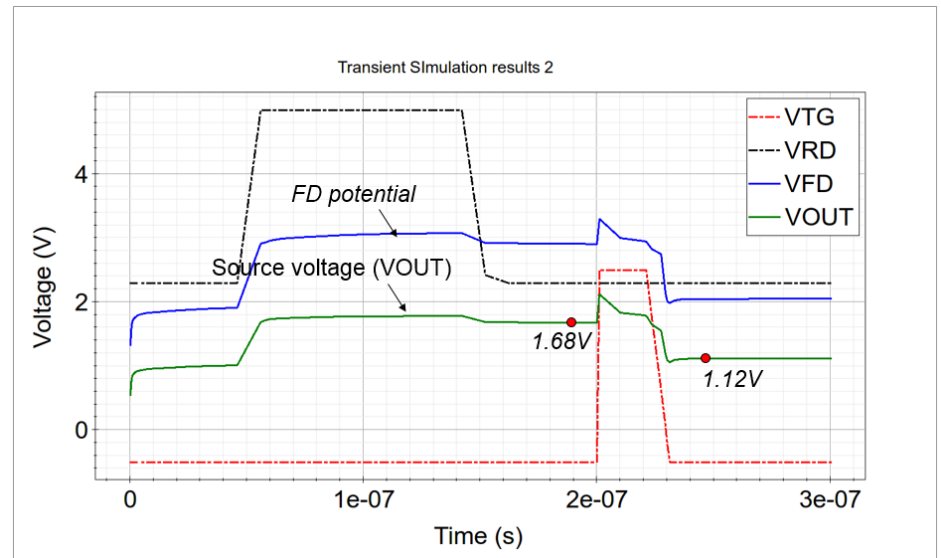
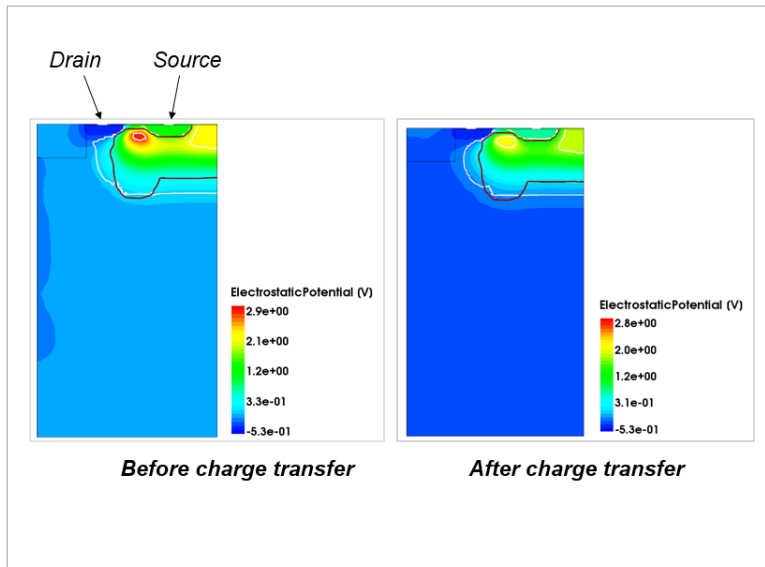
*Reduce capacitance, reduce readout noise*



# JFET source follower with FD being the virtual gate



# JFET source follower with FD being the virtual gate



## Jot device summary

	Jot	Target
Size	800nm(12L)	650nm*
Storage Capacity	100e-	1-100e-
Conversion Gain	1.7mV/e-	>1mV/e-
Read Noise	Waiting for test results	0.15e- rms

***\*65nm CIS process***

## Reference

- E.R. Fossum, ***The Quanta Image Sensor (QIS): Concepts and Challenges*** (invited) in Proc. 2011 Opt. Soc. Am. Topical Meeting on Computational Optical Sensing and Imaging, Toronto, Canada July 10-14, 2011.
- J.J. Ma, D. Hondongwa, and E.R. Fossum, ***Jot Devices and the Quanta Image Sensor***, (invited) in Technical Digest of the 2014 IEEE International Electron Devices Meeting (IEDM), pp. 247-250, San Francisco, CA December 15-17, 2014.
- J.J. Ma and E.R. Fossum, ***A Pump-Gate Jot Device with High Conversion Gain for Quanta Image Sensors***, IEEE J. Electron Devices Society, Vol. 3(2), pp. 73-77, March 2015.





***Thanks for your attention!***